

1. An array of micro-optical components comprising;
at least two micro-optical components, each micro-optical component comprising

5 a refractive surface created to have a designed optical performance, and
a corresponding compensation surface for said refractive surface, said
corresponding compensation surface including a corresponding compensation
feature when said refractive surface deviates from the designed optical
performance, said micro-optical component providing the designed optical
performance,

10 at least two refractive surfaces of the array of micro-optical components being
formed to have the designed performance, the array of micro-optical components
including at least one corresponding compensation feature, at least two compensation
surfaces of the array of micro-optical components being different from one another,
wherein at least two combinations of refractive surfaces and corresponding
15 compensation surfaces operate at different focal lengths.

2. The array of claim 1, wherein all combinations of refractive surfaces and
corresponding compensation surface operate at a same focal length.

20 3. The array of claim 1, wherein at least two combinations of refractive surfaces
and corresponding compensation surfaces operate at different focal lengths.

4. The array of claim 1, wherein said at least two refractive surfaces and said
corresponding compensation surfaces are formed on a same substrate.

25 5. The array of claim 1, wherein said at least two refractive surfaces and said
corresponding compensation profiles are formed on different substrates of at least two
substrates bonded together.

30 6. The array of claim 1, wherein corresponding compensation features correct for
aberrations in a corresponding refractive surface.

EXAMINER'S AMENDMENT

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Ms. Susan S. Morse on September 22, 2004.

The application has been amended as follows:

In claim 2, line 1, delete –7 – and insert “1”

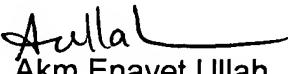
In claim 3, line 1, delete – 7—and insert “1”

Contact Information

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Akm Enayet Ullah whose telephone number is 703-308-4885. The examiner can normally be reached on Mon.-Fri. 6:30-5:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Rodney Bovernick can be reached on 703-3084819. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).


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